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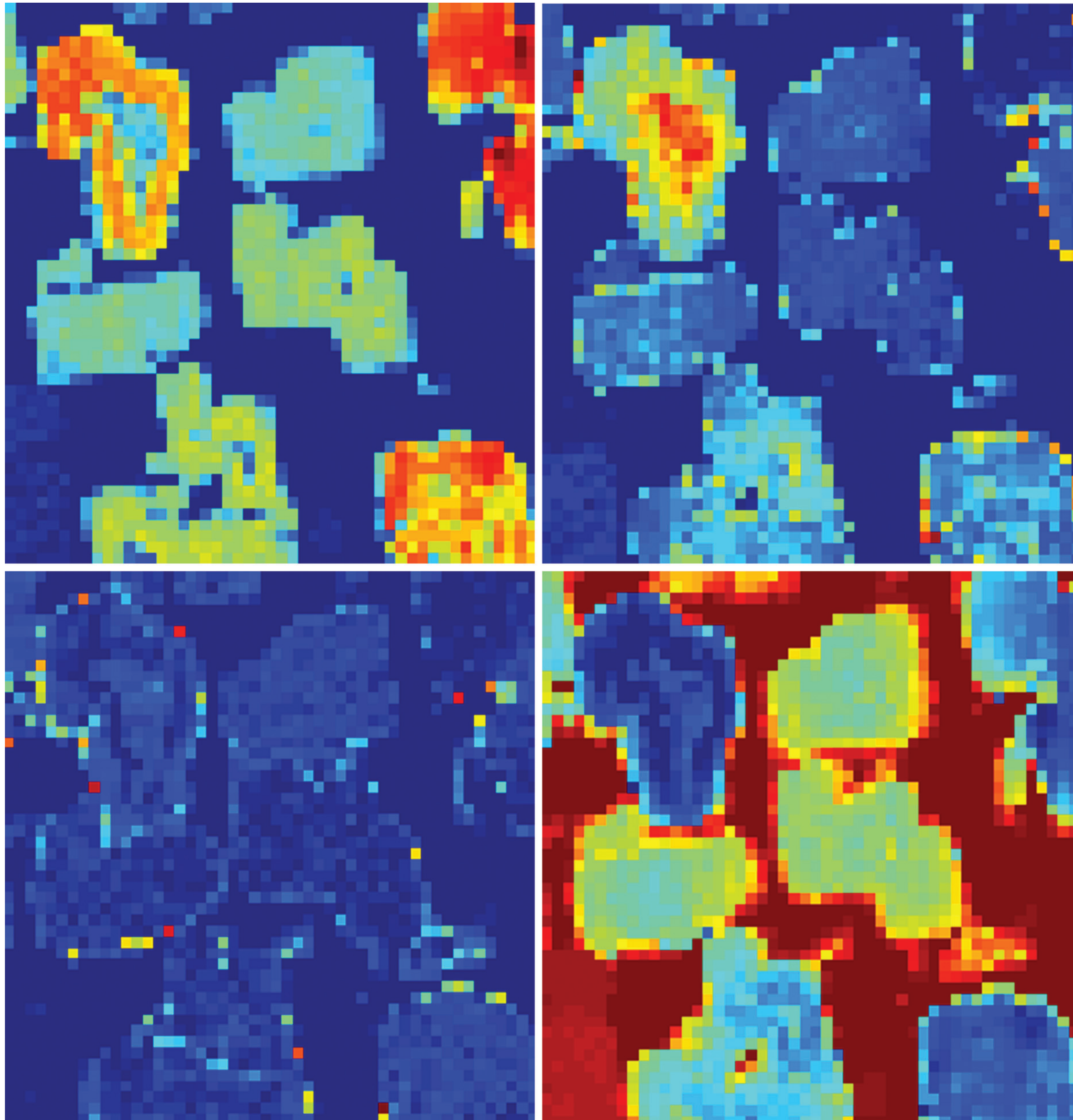

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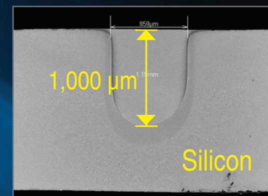

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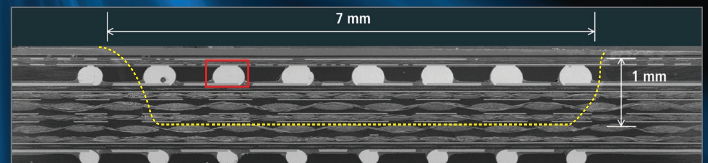

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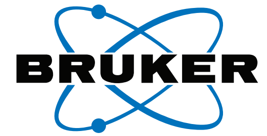

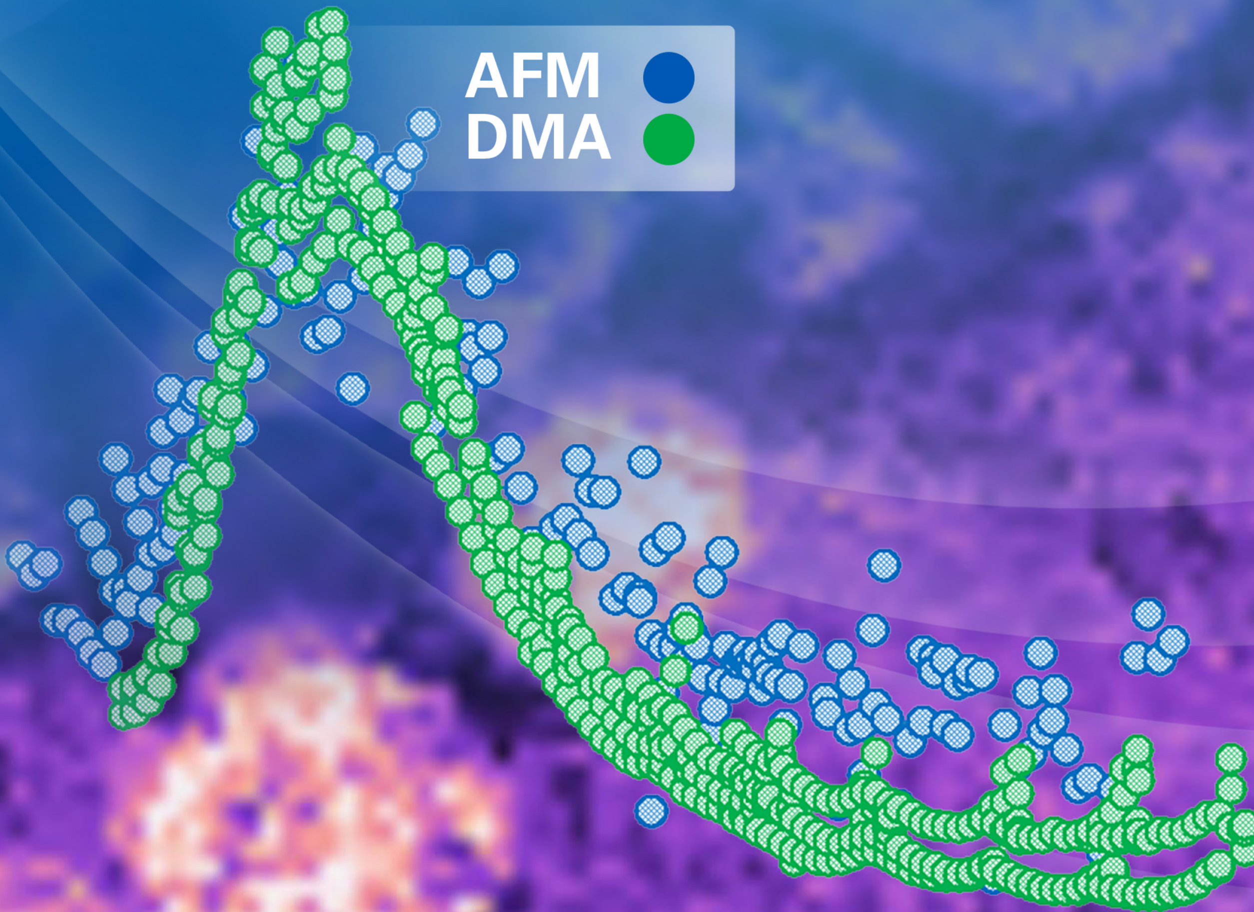

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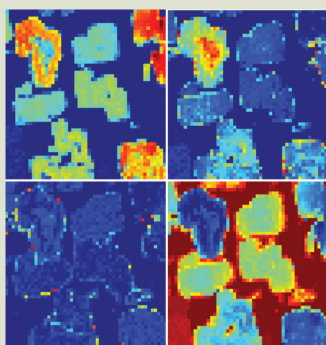

Multivariate analysis of tubular spinel-perovskite interfaces. Maps of individual transport components are clockwise from upper left: linear Ohmic component, non-linear component, low-conductivity component, and memristive component.

See article by Kalinin, Part 2.

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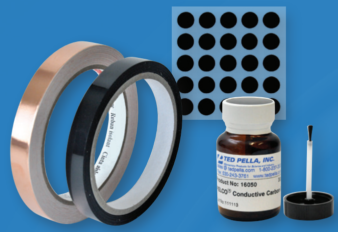
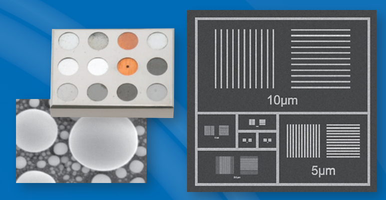


Adhesives
Conductive Tape, Carbon Tabs
Carbon, Silver & Gold



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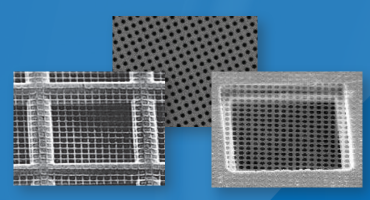

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